


<b>Search Notes</b>  	<b>Application/Control No.</b>  10508906	<b>Applicant(s)/Patent Under Reexamination</b>  ADACHI, TATSUYA
	<b>Examiner</b>  Trujillo, James K	<b>Art Unit</b>  2116

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP; Text search in cls 713/300+.	3/21/07	JKT
Updated	10/12/07	JKT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner